## **IN THE CLAIMS**

The following is a complete listing claims with a status identifier in parenthesis, which will replace all prior version and listings of claims in the application.

1. (Currently Amended) An electromagnetic interference (EMI) measuring method comprising:

acquiring a set of time-domain waveforms from a group of equably distributed test points on an Equipment Under Test (EUT) and the test points are well numbered; and

processing, including converting, comparing and analyzing the waveforms and specifying a frequency, the test point bearing the maximum value under the specified EMI frequency is foundtraced out and the position where the test point located should be the location of the EMI source.

2. (Currently Amended) The method according to claim 1, further comprising: obtaining a set of time domain signal waveforms from a group of equably distributed test points that are well numbered on the EUT;

processing the above set of time domain signal waveforms by transforming them into frequency domain or by transforming them into time/frequency domain;

comparing the EMI frequency components relating to each test point to tracefind out the test point bearing the maximum EMI amplitude; or tracingfind out the EMI frequency locations in the time domain waveform according to the time/frequency domain analysis; and

finding tracing out the position where the test point bearing the maximum EMI amplitude value in the EUT layout will be the potential EMI source location; alternatively, the electronic components in the EUT that generate the spots in the waveform should be the components generating the EMI by checking the different spots in the waveform in the time domain that correspond to the moments when the EMI occurs the time domain signal is compared with the time/frequency message, the electronic components in the EUT that generate the spots in the waveform should be the components generating the EMI.

- 3. (Previously Presented) The method of claim 1, wherein the time domain waveform could be current waveform, or voltage waveform, electromagnetic field intensity waveform.
- 4. (Currently Amended) The method of claim 1, wherein the time-domain-signal-waveform is acquired by athe measurement device, or electronic design software system.
- 5. (Previously Presented) The method of claim 1, wherein the time-domain-signals are transformed into the frequency-domain-signals by employing Fourier Transform or Wavelet Transform.
- 6. (Previously Presented) The method of claim 1, wherein the time-domain-signals are

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transformed into the time-frequency domain by employing Short Time Fourier Transform or

Wavelet Transform.

7. (Withdrawn) An EMI measuring system, comprising:

a signal acquisition portion, wherein the signal acquisition portion comprising the probe

(11) and the waveform recording circuit (12); and

a signal analysis portion, wherein the signal analysis portion comprising the data input

interface (21), the memory (22) and the time/frequency converter together with frequency

component comparator (23).

8. (Withdrawn) The system of Claim 7, wherein the data input interference (21) is the I/O

interface and the channel of the computer, or removable memory or disk, or computer memory

or hard disk.

9. (Withdrawn) The system of Claim 7, wherein the time/frequency converter and frequency

component comparator (23) are installed in the computer operation system platform and

comprises a data input module (2301), a data acquirement module (2302), a signal transform

module (2303), a frequency component comparison and analysis module (2304) and a display

module (2305).

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10. (Withdrawn) The system of Claim 7, wherein the probe (11) is the measurement device

that can pick up the current, the voltage, or the electromagnetic field intensity waveform.

11. (Withdrawn) The system of Claim 7, wherein the waveform record circuit is the

oscilloscope waveform record circuit, or the A/D card plugged directly in the computer socket,

or the A/D unit connected to computer via serial or parallel port of the data input interface (21).

12. (Currently Amended) The method of claim 2, wherein the time domain waveform is

acould be current waveform, or voltage waveform, electromagnetic field intensity waveform.

13. (Currently Amended) The method of claim 2, wherein the time-domain-signal-waveform

is acquired by athe measurement device, or electronic design software system.

14. (Previously Presented) The method of claim 2, wherein the time-domain-signals are

transformed into the frequency-domain-signals by employing Fourier Transform or Wavelet

Transform.

15. (Previously Presented) The method of claim 2, wherein the time-domain-signals are

transformed into the time-frequency domain by employing Short Time Fourier Transform or

Wavelet Transform.